

<b>Search Notes</b>				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/626,303	HUTCHENS ET AL.	
				Examiner	Art Unit	
				David J. Venci	1641	

SEARCHED			
Class	Subclass	Date	Examiner
435	174,175,1 76,177,17 8,179,180	5/25/2006	DV
435	181,182	5/25/2006	DV
435	187,188	5/25/2006	DV
435	287.1	5/25/2006	DV
435	287.2	5/25/2006	DV
435	287.7	5/25/2006	DV
435	287.9	5/25/2006	DV
435	288.3	5/25/2006	DV
435	288.4	5/25/2006	DV
435	288.6	5/25/2006	DV
435	803,814	5/25/2006	DV
435	815,970	5/25/2006	DV
435	973	5/25/2006	DV
435	DIG.45	5/25/2006	DV

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
updated (see above)		5/25/2006	DV

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST/WEST	5/25/2006	DV
PUBMED	5/25/2006	DV
SCIENCECIRECT	5/25/2006	DV
STN - see attached	5/25/2006	DV
PALM - inventor name search	5/25/2006	DV
Patentability Conference - Long Le (SPE 1641), Bruce Campbell (SPE 1648)	5/25/2006	DV

Search Notes (continued)	Application/Control No.	Applicant(s)/Patent under Reexamination
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SEARCHED			
Class	Subclass	Date	Examiner
436	518,523,5 24,525,52 6,527,528	5/25/2006	DV
436	529,530	5/25/2006	DV
436	531,532	5/25/2006	DV
436	535,161	5/25/2006	DV
436	162,173	5/25/2006	DV
436	174,175	5/25/2006	DV
436	176,177	5/25/2006	DV
436	178,809	5/25/2006	DV
436	825	5/25/2006	DV
422	69,70,78	5/25/2006	DV
422	80,186.01	5/25/2006	DV
422	186.02	5/25/2006	DV
422	236,906	5/25/2006	DV
422	942,946	5/25/2006	DV

Search Notes (continued)	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/626,303	HUTCHENS ET AL.
	Examiner	Art Unit
	David J. Venci	1641

SEARCHED			
Class	Subclass	Date	Examiner
422	947,948	5/25/2006	DV
210	660,663	5/25/2006	DV
210	695	5/25/2006	DV
204	157.15	5/25/2006	DV
204	546	5/25/2006	DV
204	403.01	5/25/2006	DV
204	403.03	5/25/2006	DV
204	403.04	5/25/2006	DV
250	281,282	5/25/2006	DV
250	288	5/25/2006	DV
530	413,416	5/25/2006	DV
118	102,624	5/25/2006	DV
118	717	5/25/2006	DV
427	2.13,466	5/25/2006	DV

## **Search Notes (continued)**



**Application/Control No.**

10/626,303

Examiner

David J. Venci

**Applicant(s)/Patent under  
Reexamination**

HUTCHENS ET AL.

## **Art Unit**

1641

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner